



US007911872B2

(12) **United States Patent**
Lakhani et al.

(10) **Patent No.:** **US 7,911,872 B2**
(45) **Date of Patent:** ***Mar. 22, 2011**

(54) **COLUMN/ROW REDUNDANCY ARCHITECTURE USING LATCHES PROGRAMMED FROM A LOOK UP TABLE**

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 72 days.
This patent is subject to a terminal disclaimer.

(21) Appl. No.: **12/371,052**

(22) Filed: **Feb. 13, 2009**

(65) **Prior Publication Data**

US 2009/0147599 A1 Jun. 11, 2009

Related U.S. Application Data

(63) Continuation of application No. 11/508,325, filed on Aug. 23, 2006, now Pat. No. 7,505,357, which is a continuation of application No. 10/206,044, filed on Jul. 29, 2002, now Pat. No. 7,120,068.

(51) **Int. Cl.**
G11C 8/00 (2006.01)

(52) **U.S. Cl.** **365/230.08**; 365/233.5; 365/200; 365/225.7

(58) **Field of Classification Search** 365/230.08, 365/233.5, 225.7

See application file for complete search history.

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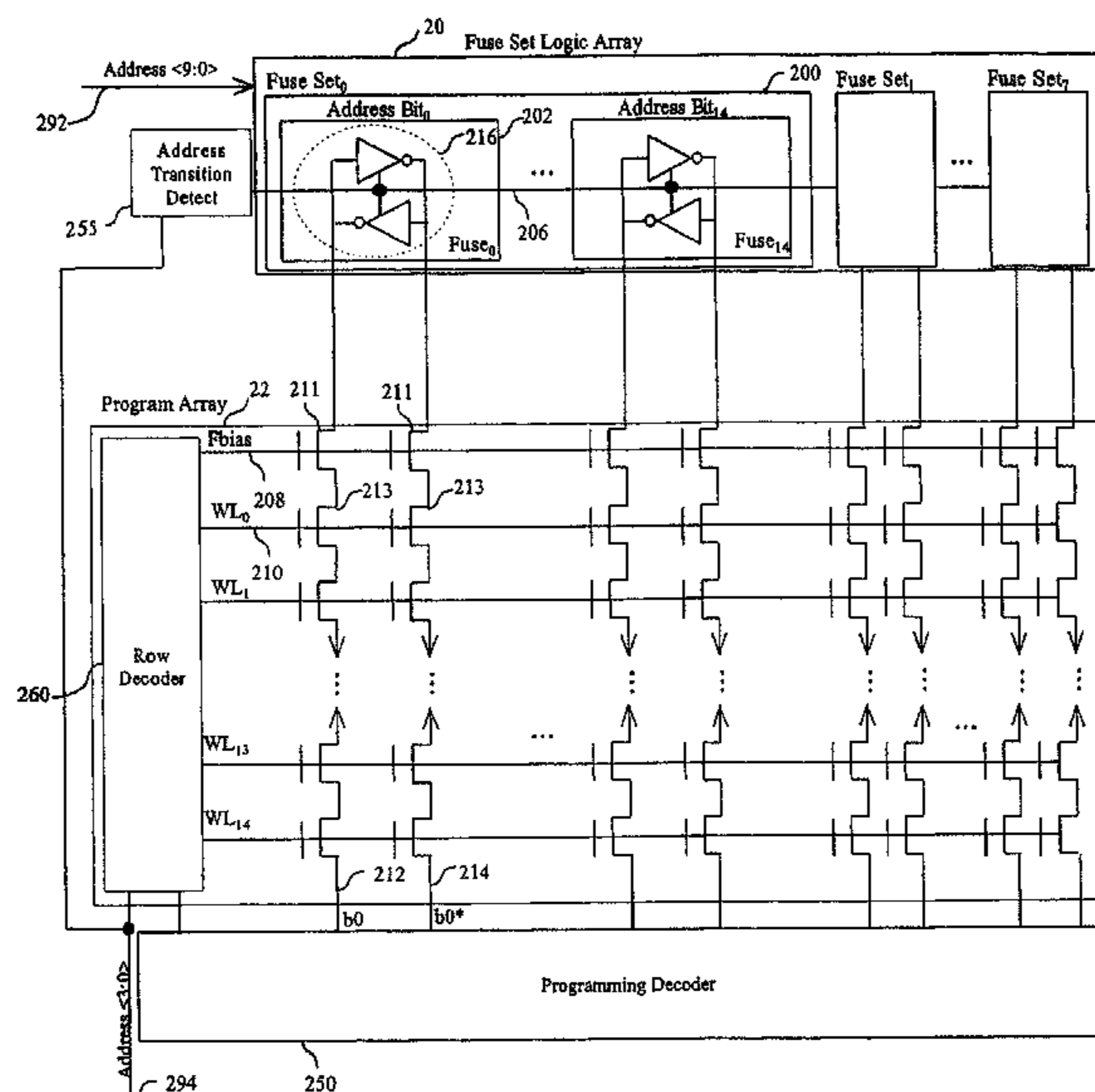
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(57) **ABSTRACT**

A scheme for defective memory column or row substitution is disclosed which uses a programmable look-up table to store new addresses for column selection when certain column or row addresses are received. The new addresses are loaded into a programmable fuse latch each time an address transition is detected in the input address.

24 Claims, 7 Drawing Sheets



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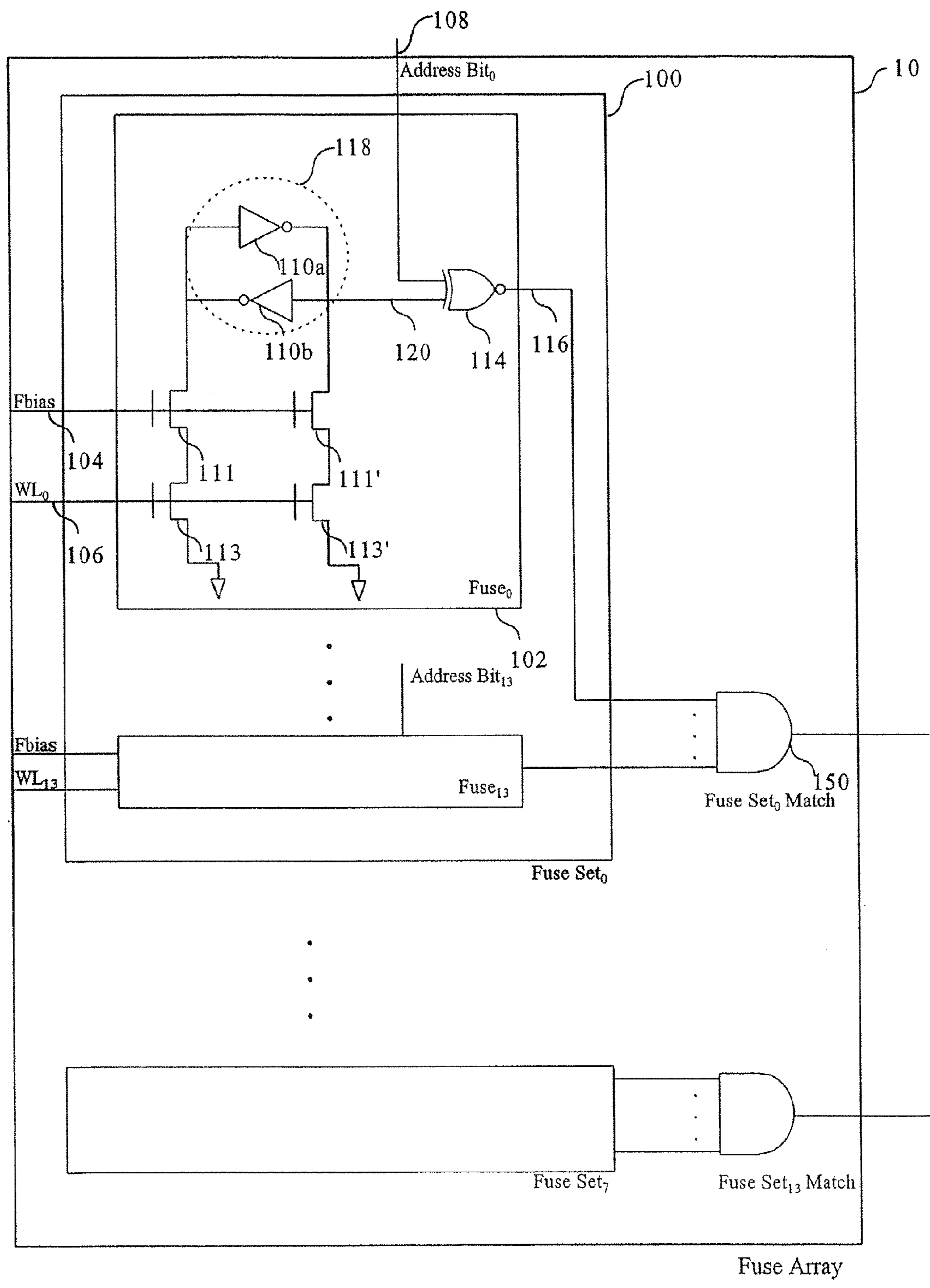


FIG. 1 (Prior Art)

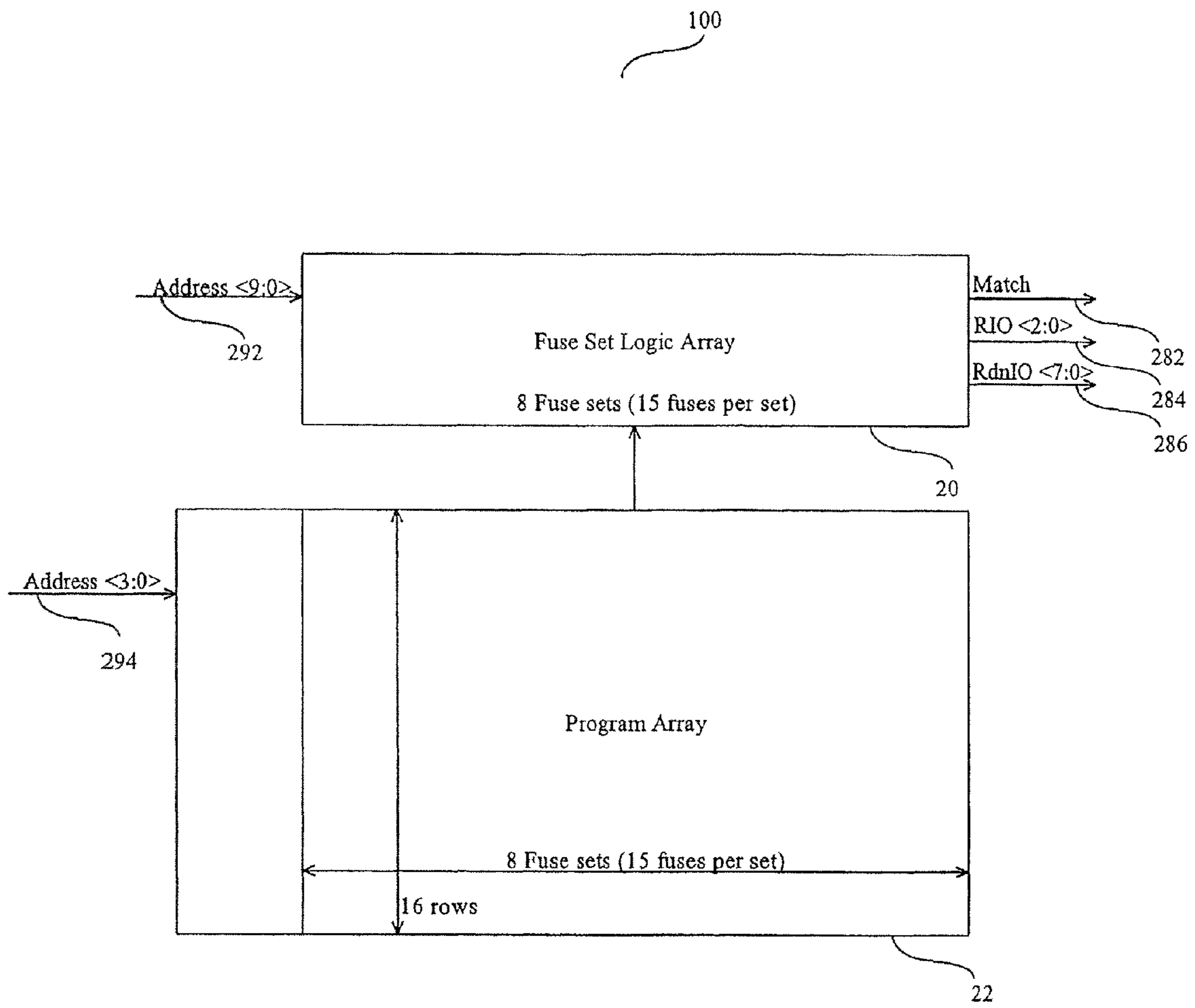


FIG. 2

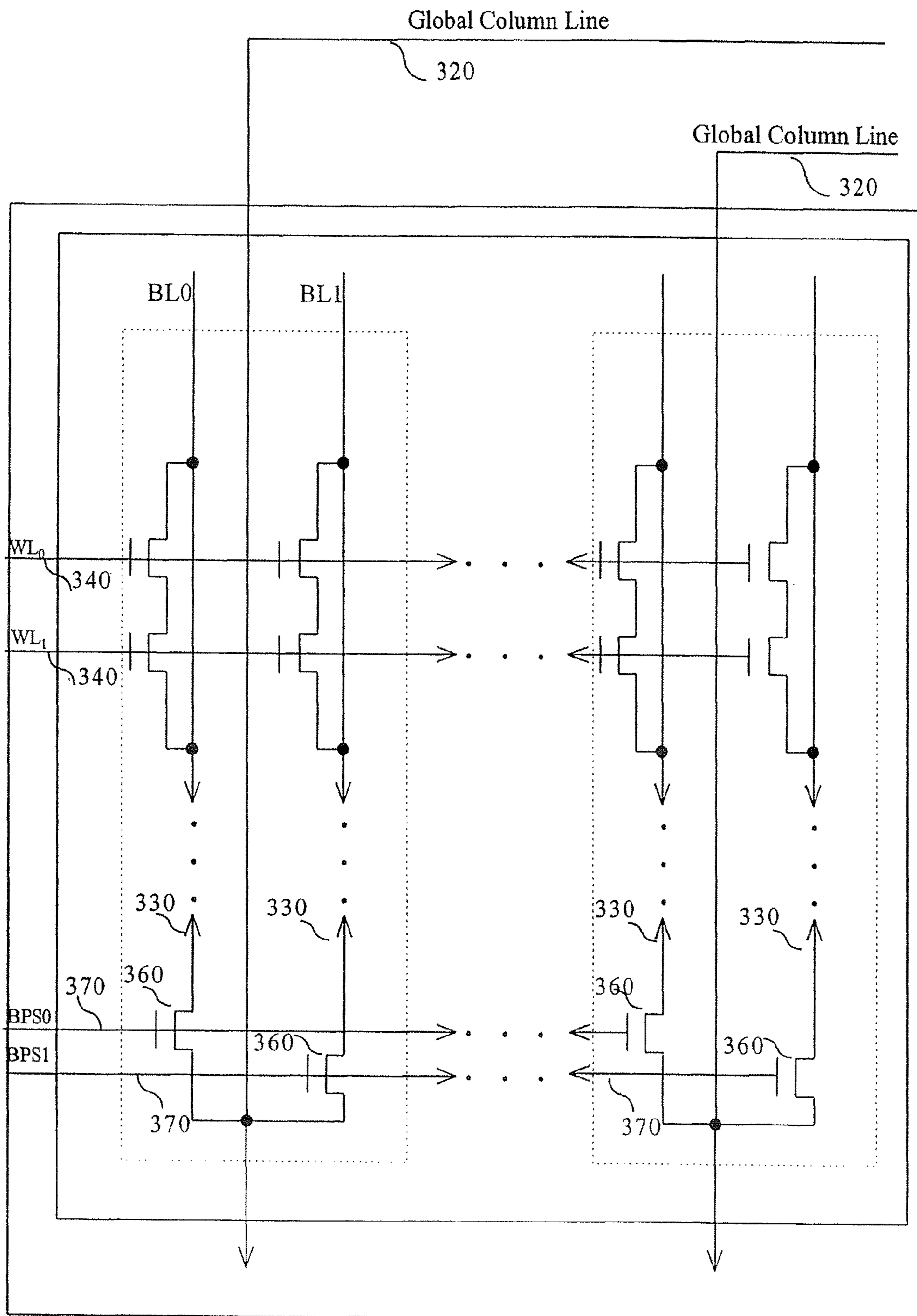


FIG. 3

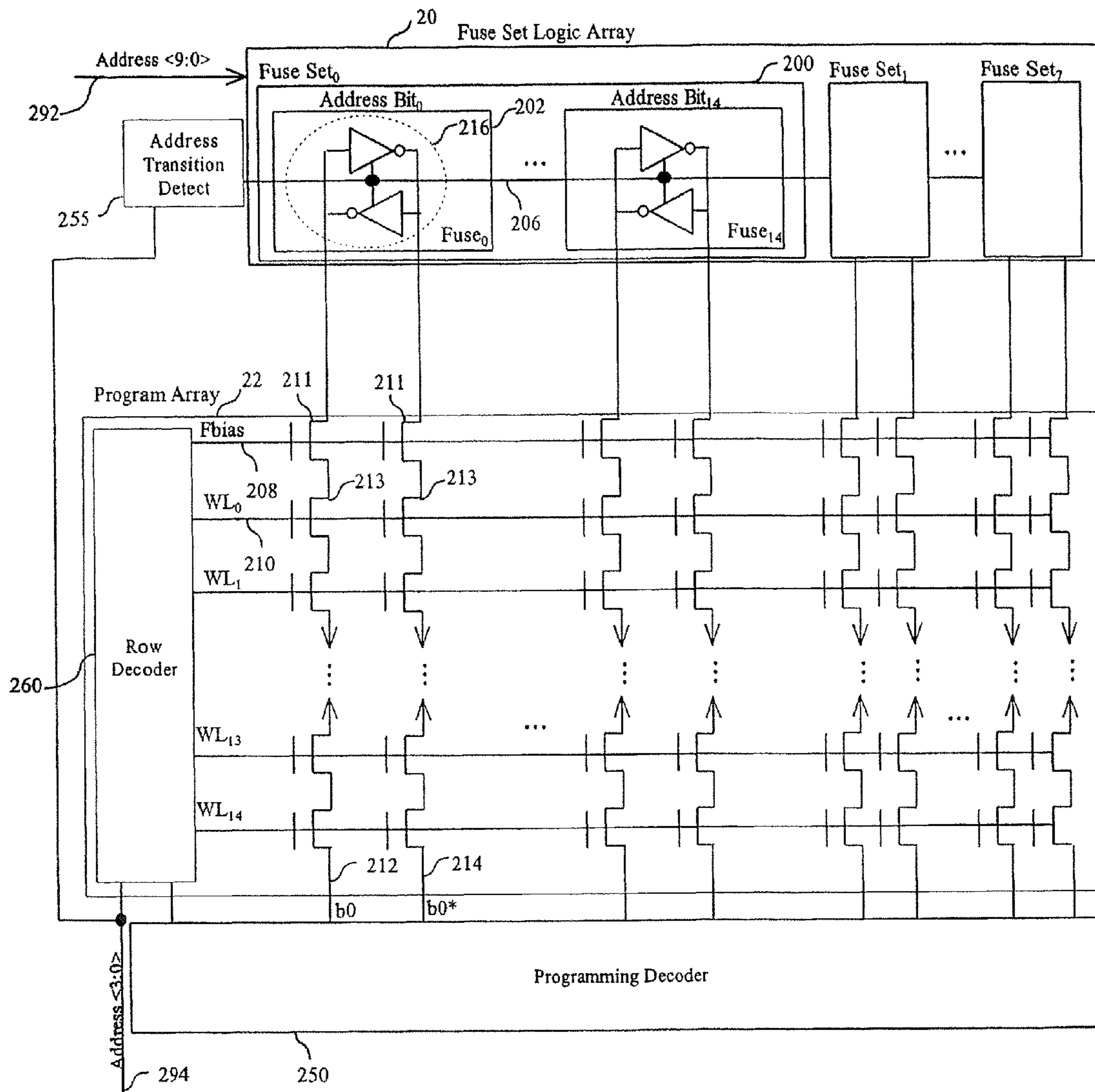


FIG. 4

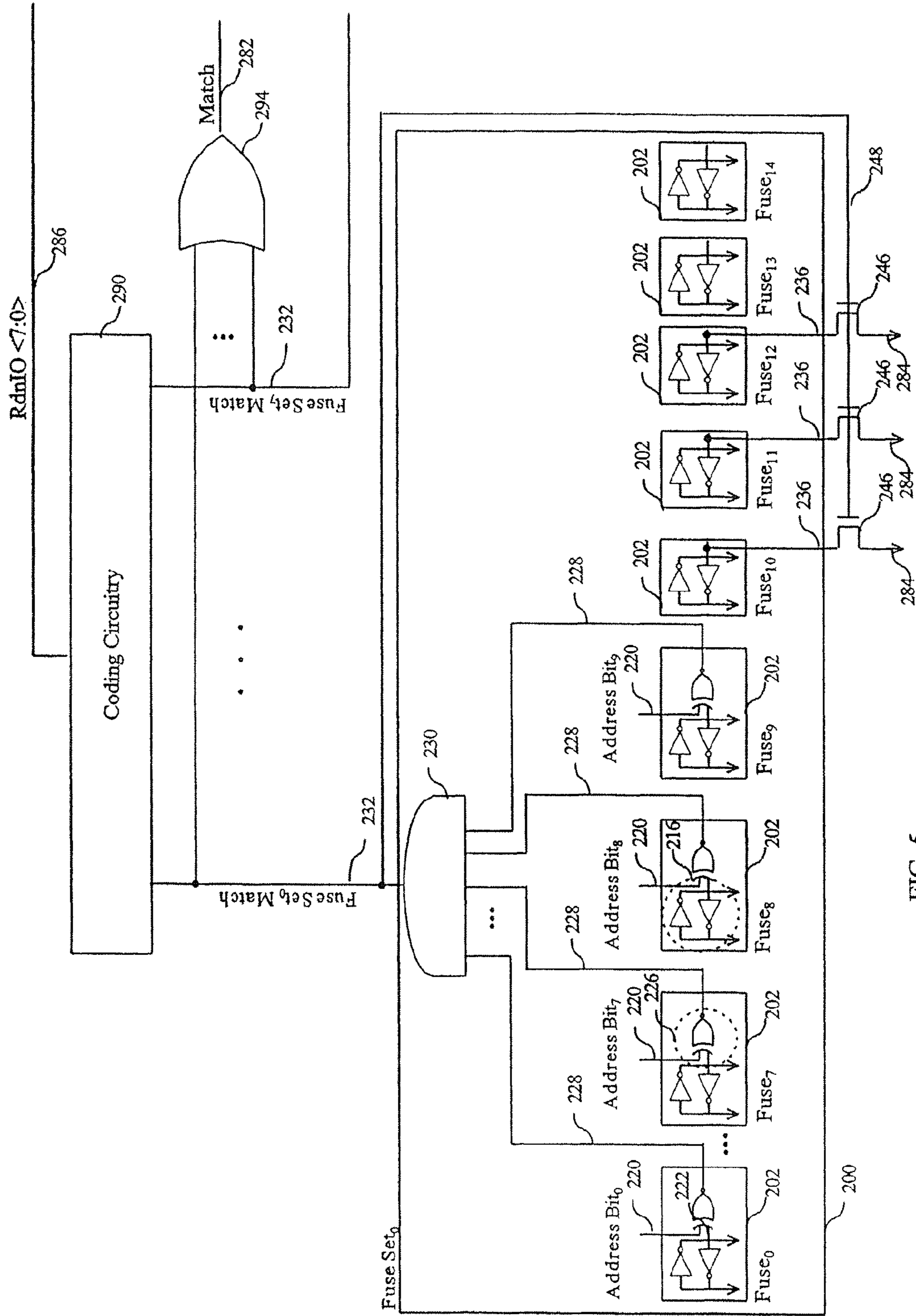


FIG. 5

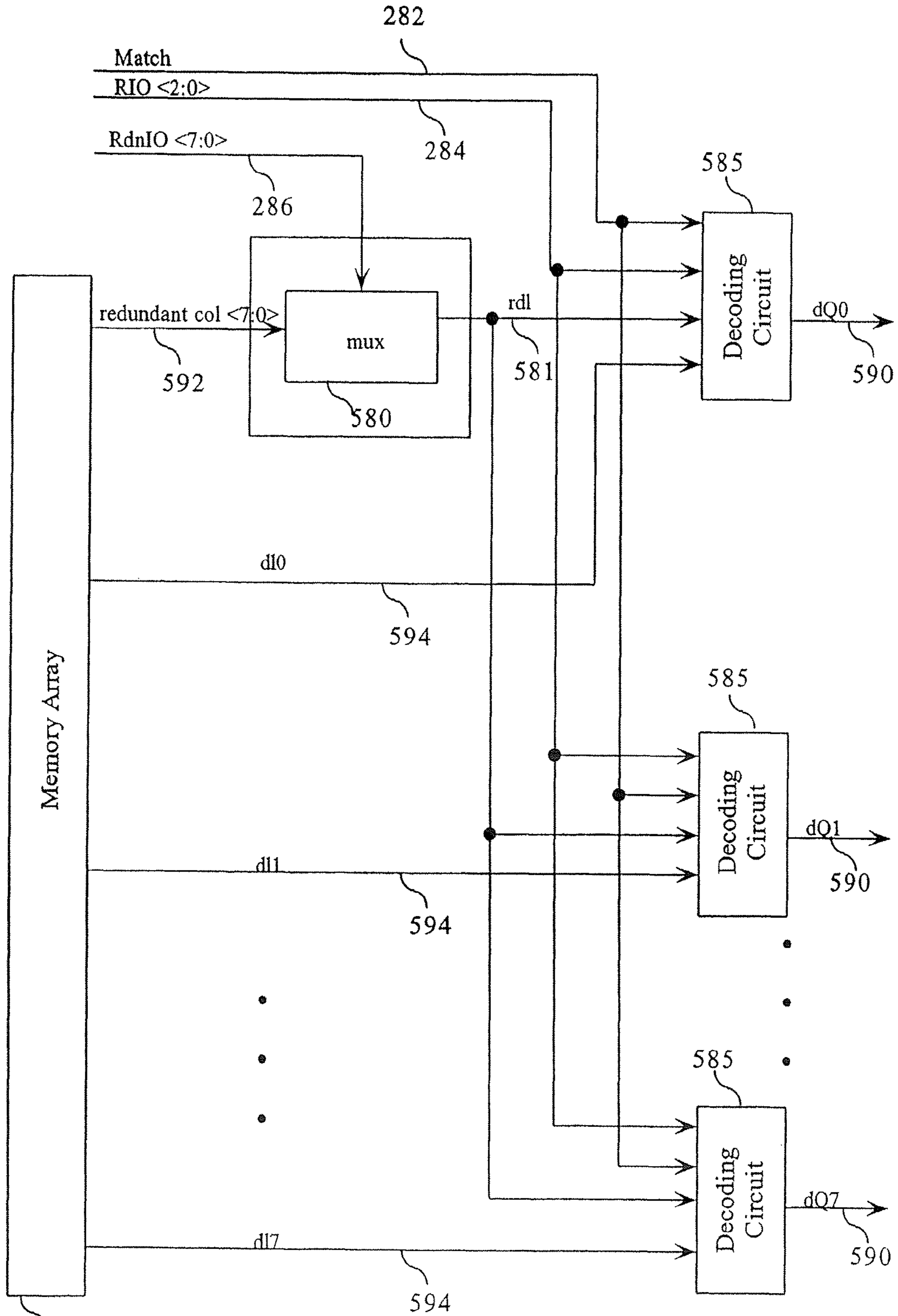
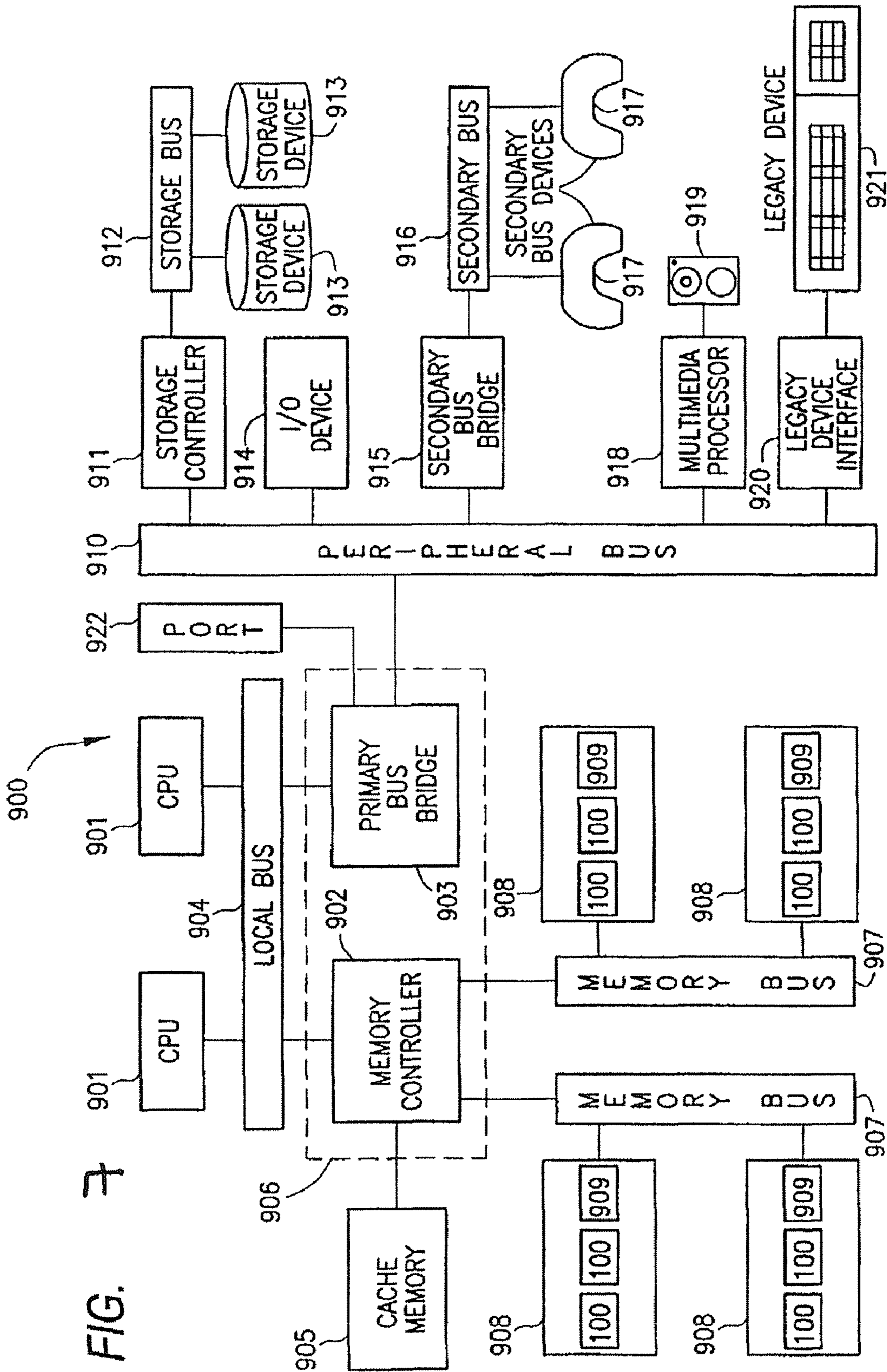


Fig. 6



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**COLUMN/ROW REDUNDANCY
ARCHITECTURE USING LATCHES
PROGRAMMED FROM A LOOK UP TABLE**

CROSS REFERENCE TO RELATED
APPLICATIONS

The present application is a continuation of U.S. patent application Ser. No. 11/508,325, filed Aug. 23, 2006, now U.S. Pat. No. 7,505,357 which is a continuation of U.S. patent application Ser. No. 10/206,044, now U.S. Pat. No. 7,120,068, filed on Jul. 29, 2002, the disclosures of which are incorporated by reference in their entirety.

FIELD OF THE INVENTION

This invention relates to the field of memory devices and more particularly, to a column/row redundancy architecture for semiconductor memory.

BACKGROUND OF THE INVENTION

As memory chip manufacturers strive to decrease die size, and increase capacity and speed they must contend with an increased percentage of defective, or faulty memory cells. Different approaches have been taken to overcome detected memory cell defects. One approach has been to "repair" out a defective memory column or row by "flagging" the defective column or row and using redundant columns or rows of memory cells that are substituted for defective columns or rows. A defective region is marked as defective by blowing fuses, or anti-fuses, or lasers are used to etch circuits, to set latches which remap the defective column or row to a non-defective fully-operable redundant column or row. With this re-mapping, attempts to address the defective column or row will be redirected to address the redundant column or row known to be properly working.

Referring to FIG. 1, a portion of a conventional column redundancy repair fuse array **10** for a flash memory is shown. Fuse Array **10** contains a series of eight fuse sets **100**, although only two fuse sets, Fuse Set₀ and Fuse Set₇, are shown for simplicity. The eight fuse sets **100** permit the redirecting of eight defective addressed columns to eight operable redundant columns. Each fuse set **100** contains fourteen fuses **102**, Fuse₀ . . . Fuse₁₃, although only fuses Fuse₀ and Fuse₁₃ are shown in FIG. 1 for simplicity. Each fuse **102** stores one bit of an address and contains a latch **118** formed of a pair of inverters **110a** and **110b**. An Fbias control line **104** acts on transistors **111**, **111'** which form an isolation circuit for the latch **118**. When the Fbias control line **104** is enabled and word line WL0 **106** is enabled, a complementary bit pattern stored in flash transistors **113**, **113'**, representing a stored address bit is written to latch **118**. Disabling the Fbias **104** isolates the latch **118** from the storage transistors **113**, **113'** for programming of transistors **113**, **113'**.

Thus, each fuse **102**, e.g. Fuse₀, in FIG. 1, stores in the associated latch **118** one address bit that is used for comparison with a corresponding bit of an incoming column address. For example, the first bit, Address Bit₀, of an incoming address will be input to XOR gate **114** which compares the address bit to the address bit stored in latch **118**. The result of the comparison is output through conductive line **116**. If the logic value of Address Bit₀ is the same as the logic value of stored in latch **118** then conductive line **116** will carry a logic value of one. If they are not the same, then conductive line **116** will carry a logic value of zero. The resulting output of each of the Fuse₀ . . . Fuse₁₃ in the fuse set₀ **100** are then compared

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in AND gate **150**, to see if all of the incoming address bits are the same as all of the corresponding latch stored values. Each fuse set **100** is associated with a unique redundant column in a memory array. Thus, if there is an address match detected by AND gate **150** for a memory access a redundant column is utilized in place of the original defective column.

The problem with this approach is that since each fuse set **100** is permanently set with the address of a defective column, the number of defective columns which can be repaired is limited by the number of fuse sets **100** fabricated on the die. In the prior art example of FIG. 1, only eight defective columns may be re-addressed. Additionally, fuse arrays **10** consume die space. Accordingly, adding more fuse sets **100** to provide increased repair possibilities unduly increases die size.

BRIEF SUMMARY OF THE INVENTION

The present invention implements column or row redundancy using a single group of reloadable latches and associated XOR logic, which upon a change in an incoming address dynamically reloads the latch with new redundancy information associated with the specific incoming addresses. Since the latches are reloaded with new redundancy addresses for each incoming address transition, a given capacity of redundant columns or rows can be accommodated with fewer fuse circuit elements. This provides for considerable die area savings compared to traditional implementations of column or row redundancy.

In a preferred embodiment the present invention provides redundant global columns or redundant rows for each memory array bank and repairs out a faulty global column or row with a redundant global column or redundant row. A defective global column or row address is stored in a programmable look up table and is loaded into address latches for comparison in an XOR gate with incoming global column or row addresses. For column repair the look up table also includes stored information assigning the redundant column to a particular location in an output path.

These and other features and advantages of the invention will be more readily understood from the following detailed description of the invention which is provided in connection with the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a representational schematic diagram of a column repair circuit in the prior art;

FIG. 2 is a block diagram of a column repair circuit in one embodiment of the present invention;

FIG. 3 is a schematic diagram of a flash memory array in one embodiment of the present invention;

FIG. 4 is a schematic diagram showing further details of the FIG. 2 embodiment;

FIG. 5 is a schematic diagram showing further details of the FIG. 2 embodiment;

FIG. 6 is a schematic diagram showing circuitry for defective column replacement; and

FIG. 7 is a block diagram of a processor system utilizing a method and apparatus of the present invention.

DETAILED DESCRIPTION OF THE INVENTION

The present invention can be used for substitution of a redundant memory line containing memory elements for a defective memory line containing memory elements. The invention can be used to substitute a redundant column line

for a defective column line, or for substitution of a redundant row line for a defective row line in a memory device. However, to simplify the description, the invention will be described in connection with the substitution of a redundant column for a defective global column in a flash memory device. It should be understood, however, that the invention can be used to substitute a redundant column for a defective column or a redundant row for a defective row in any type of memory device.

During memory device testing when a defective column is detected its address is stored in a lookup table, where the column maybe a global column. After testing, when the memory array is in use, a memory access to an identified defective column is remapped to a redundant column using the address stored in the look up table. The look up table contains rows of memory devices for use in storing the addresses of defective columns. The look up table rows are addressed whenever a sector or block address transition is detected. The column address stored in the addressed look up table row is loaded into latches of a fuse set logic array for comparison to an incoming global address. If an incoming column address matches an address in the fuse set logic array, then a redundant column is activated and used in place of a defective column. This process for determining defective column addresses and redirecting is described below. In this manner, the fuse set logic array is not limited to comparing only one address per fuse set, but can be loaded upon a change in sector or block addressing with different defective column addresses for comparison with an incoming address) thereby enabling a given number of fuse sets of a fuse array to handle a larger number of defective columns than the number of fuse sets.

FIG. 2 is a block diagram of an exemplary embodiment of the present invention and comprises a fuse set logic array **20** and a program array **22** in the form of a look up table. The fuse set logic array **20** contains the latches and address comparator; it compares a incoming column address, carried into the fuse set logic array **20** on line **292**, with a stored address from program array **22** and set into the latches in logic array **20** corresponding to a defective column. A match is indicated if the incoming address corresponds to the stored address and is indicated on line **282**. Furthermore, re-addressing information also contained in the program array **22** and loaded into latches of logic array **20** is carried on RIO $\langle 2:0 \rangle$ lines **284**. Additional readdressing information determined by the logic array **20** is carried on RdnIO $\langle 7:0 \rangle$ lines **286**. In this exemplary embodiment, the fuse set logic array **20** has eight (8) fuse sets, with fifteen (15) fuses in each fuse set. Each fuse set represents a redundant column which is remapped from a defective column.

The program array **22** is a lookup table that stores the addresses of defective columns and substitute redundant column information. In this embodiment, the program array **22** has sixteen (16) rows and one hundred twenty columns of memory cells for storing information. Each row contains eight (8) fuse sets each containing fifteen (15) bits and their complements of column information. This corresponds to storage of sixteen (16) sets, one per row, of redundant column information with each set containing eight stored defective addresses, one for each fuse set in logic array **20**.

When a portion of an incoming higher order address, e.g., the sector or block address, carried on line **294** to the program array **22**, indicates a sector or block change, the corresponding information for the defective columns in that sector or block stored in program array **22** is loaded into fuse set logic

array **20** for use in comparison with an incoming address and for output of remapping information on output lines **284** and **286**.

FIG. 3 illustrates a portion of a flash memory array with which the invention may be used having multiple global column lines **320**, associated with local column (bit) lines BL_0, BL_1, \dots and multiple row lines WL_0, WL_1, \dots . In this flash memory array, a global column line is coupled to several "local" column lines. Control lines **370** BPS0 & BPS1 act on transistors **360, 360'** to form an isolation circuit for the local column lines **330** from the global column line **320**. Enabling the transistors **360, 360'** couples the respective local column line **330** to the global column line **320**.

FIG. 4 illustrates a portion of the fuses **202** containing latches **216** for the fuse set Fuse Set₀ of logic array **20** (FIG. 2) as well as a portion of the rows and columns of the program array **22** for storing information which is loadable into the latches **216**. One of the advantages of the present invention is that the latches **216** are reloadable with information from program array **22** which simplifies the circuitry of the fuse set logic array **20**. During the testing of the memory, the addresses of defective global memory columns, as well as information indicating where a redundant global column is to be used for substitution in the data output circuit are stored in the rows of program array **22**, indicated by the row word lines $WL_0 \dots WL_{14}$. The latches **216** of fuses **202** of the fuse set logic array of FIG. 4 are loaded with information from the program array **22** each time a column sector address transition is detected by address transition detect circuit **255**. As noted, in the illustrated embodiment, the fuse set logic array **20** has eight (8) fuse sets **200** (Fuse Set₀ . . . Fuse Set₇), each of which contains fifteen (15) fuses **202** (Fuse₀ . . . Fuse₁₄). Each fuse set **200**, when loaded, contains information identifying a defective column and further identifying where a redundant column associated with the fuse set **200** is to be used in an output data path. Although particular address sizes, numbers of fuses and numbers of fuse sets are used for illustrative purposes, these values are not limiting.

The program array **22** loads the fuse set array **20** with information when an address transition to a different memory sector or block is detected. An address which corresponds to four bits $\langle 3:0 \rangle$ of a sector or block address which corresponds to an incoming column address $\langle 9:0 \rangle$ carried on line **292** and identifying a sector or block, is carried on line **294** and decoded by address transition detection circuit **255** and the row decoder **260**. The row decoder **260** decodes the 4 bit sector or block address $\langle 3:0 \rangle$ and activates a corresponding one of the row word lines $WL_0 \dots WL_{14}$, when address transition detection circuit **255** detects that a sector or block address transition has occurred by a change in the contents of the sector or block address $\langle 3:0 \rangle$. It then outputs a signal on line **206**, permitting latch **216** to be loaded with data from memory cells associated with the selected word line ($WL_0 \dots WL_{14}$) from the program array **20**. The Fbias line **208**, acting as an isolation circuit, enables transistor **211** and permits latch **216** to be loaded. The Fbias line is also used to isolate the latches **216** from the program array **22** during programming of the array by programming decoder **250**. It should be noted that data is stored in program array **22** using flash memory transistors connected at their gates to the word lines $WL_0 \dots WL_{14}$.

Thus, the row decoder **260** decodes the sector or block address $\langle 3:0 \rangle$ on line **294**, activates the appropriate word line **210** ($WL_0 \dots WL_{14}$) to load the data from the selected word line into latches **216**. After time sufficient to load latches **216** with the logic states, the Fbias line **208** is subsequently disabled, thereby isolating the latches **216** from program array

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22. In another embodiment, the Fbias line 208 and word line 210 remains enabled. The information loaded from the program array 22 remains stored in the latches 216. In this exemplary embodiment, data loaded from the program array 22 contains ten (10) bits of address data for comparison with an incoming column address and five (5) bits of re-addressing data.

FIG. 5 represents a more detailed illustration of the fuses 202 in Fuse Set₀ 200 of FIG. 4. It should also be noted that data is stored in the flash memory transistors of program array 22 in complementary fashion. Thus, each data element is stored as a 01 or 10 pattern which pattern is applied to each latch 216 from program array 22. FIG. 5 illustrates how each of the latches 216 for fuses Fuse₀ . . . Fuse₉, which is loaded with a bit of an address of a defective column has its output coupled to one input of an XOR gate 222. The XOR gate 222 also receives at its other input a corresponding bit of an incoming column address on line 220. Thus, XOR gates 222 are used as part of an address comparator; the other part of the address comparators being AND gate 230.

The address comparators formed by logic gates 222 and 230 compares an incoming address <9:0> in line 220 with the addresses stored in the fuse sets 200 to determine if the incoming address is a defective address. In the embodiment shown, the ten (10) bits of the incoming address on lines 220 are compared to the ten (10) bits of the stored memory address stored in latches 216. If all ten (10) of the incoming address bits match all ten (10) stored address bits in a single fuse set 200, then a match is true as indicated at the output of AND gate 230, indicating that a defective column is being addressed and that column substitution is to take place.

The information stored in the latches of fuses Fuse₁₀, . . . Fuse₁₂ provides redundant column location information for the output circuit and its use is described below. Lines 284 of FIG. 5 correspond to tie output RIO <2:0> shown in FIG. 2. The information stored in the latches 216 in Fuse₁₀ . . . Fuse₁₂, represent which output line of multiple bit output lines dQ₀ . . . dQ₇ a redundant column associated with Fuse Set₀ should be coupled to. The data on lines 284 must pass through pass gates 246 which are activated whenever AND gate 230 of Fuse Set₀ indicates an address match. Therefore, the only control information on lines 284 RIO <2:0> is derived from the fuse set 200 which corresponds to a matched incoming address. The fuses Fuse₁₃ and Fuse₁₄ can receive additional information from the look up table, such as enable or disable information which can be used as control information. Although the exemplary embodiment indicates three bits of addressing information (e.g., <2:0>) being used for the RIO, other embodiments may use different number of bits, for example, eight bits might be used.

If a match occurs, a redundant column replaces the addressed defective column. As indicated above, part of the readdressing information contained in the program array 22 and loaded into the latches of the logic array 20 is carried on RIO <2:0> lines 284. The other readdressing information is determined by the logic array 20. Using the result of the comparison of each fuse set 200 output on lines 232 coding circuitry 290 generates a mask data reflecting which fuse set 200 of the eight fuse sets 200 indicates an address match and outputs the result on line 286 by making one of the eight bit patterns RdnIO <7:0> different from the others. For example, if an incoming address matches the address stored in latches in second fuse set 200, Fuse Set₁, then the coding circuitry 290 generates "00000010" indicating that Fuse Set₁ had a match. FIG. 5 also generates another match signal on line 282 from OR gate 294 whenever any one of fuse sets 200 has a defective address match.

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FIG. 6 illustrates the memory output circuitry that substitutes a defective column with a redundant column. A multiplexer 580 selects a redundant column associated with the fuse set 200 which had an address match to replace the defective column based on the selection information carried on line 286 which indicates which of the eight redundant columns input to multiplexer 580 is to be used for substitution. The result of the selection is output on line 581. For example, if the information carried on line 286 indicates that the second redundant data line associated with the second fuse set is to be used for substitution, i.e., "00000010", then the second redundant column of the eight redundant columns on lines 592 is switched by multiplexer 580 to line 581.

Lines 594 carry the normal column data from memory array 560 into each of the eight I/O decoding circuits 585. Decoding circuits 585 also input the redundant column information on line 581, selection information RIO <2:0> on line 284 and a match value on line 282. Using the selection information RIO <2:0> the decoding circuit 585 selects between the redundant column on lines 581 and column data on lines 594 to be output from the circuit. For example, if the logic value of the match line 282 is false, which indicates no defective column address was matched, the information carried on lines 594 is output on lines 590. If, however, the match value has a logical value of true, then the selection information carried on lines 284 is applied to the decoding circuits 585 instructing one of them to substitute the redundant data line 581 for the actual column data line 594.

For example, if RIO <2:0> indicates that column line dQ1, associated with the data input/output line dQ1 is defective and is to be replaced by a redundant column line, then the decoding circuit 585 associated with output line dQ1 will use the redundant column on line 581 to replace the dQ1 line coming into decoding circuit 585 and output the redundant column information as output data dQ1 on line 590.

FIG. 7 illustrates an exemplary processing system 900 which may utilize the memory device 100 of the present invention constructed as a flash memory as a DRAM or other type of memory device. The processing system 900 includes one or more processors 901 coupled to a local bus 904. A memory controller 902 and a primary bus bridge 903 are also coupled the local bus 904. The processing system 900 may include multiple memory controllers 902 and/or multiple primary bus bridges 903. The memory controller 902 and the primary bus bridge 903 may be integrated as a single device 906.

The memory controller 902 is also coupled to one or more memory buses 907. Each memory bus accepts memory components 908 which include at least one memory device 100 incorporating the present invention. The memory components 908 may be a memory card or a memory module. Examples of memory modules include flash memory cards, single inline memory modules (SIMMs) and dual inline memory modules (DIMMs). The memory components 908 may include one or more additional devices 909. For example, in a SIMM or DIMM, the additional device 909 might be a configuration memory, such as a serial presence detect (SPD) memory. The memory controller 902 may also be coupled to a cache memory 905. The cache memory 905 may be the only cache memory in the processing system. Alternatively, other devices, for example, processors 901 may also include cache memories, which may form a cache hierarchy with cache memory 905. If the processing system 900 include peripherals or controllers which are bus masters or which support direct memory access (DMA), the memory controller 902 may implement a cache coherency protocol. If the memory controller 902 is coupled to a plurality of

memory buses **907**, each memory bus **907** may be operated in parallel, or different address ranges may be mapped to different memory buses **907**.

The primary bus bridge **903** is coupled to at least one peripheral bus **910**. Various devices, such as peripherals or additional bus bridges may be coupled to the peripheral bus **910**. These devices may include a storage controller **911**, a miscellaneous I/O device **914**, a secondary bus bridge **915**, a multimedia processor **918**, and an legacy device interface **920**. The primary bus bridge **903** may also coupled to one or more special purpose high speed ports **922**. In a personal computer, for example, the special purpose port might be the Accelerated Graphics Port (AGP), used to couple a high performance video card to the processing system **900**.

The storage controller **911** couples one or more storage devices **913**, via a storage bus **912**, to the peripheral bus **910**. For example, the storage controller **911** may be a SCSI controller and storage devices **913** may be SCSI discs. The I/O device **914** may be any sort of peripheral. For example, the I/O device **914** may be a local area network interface, such as an Ethernet card. The secondary bus bridge may be used to interface additional devices via another bus to the processing system. For example, the secondary bus bridge may be an universal serial port (USB) controller used to couple USB devices **917** via to the processing system **900**. The multimedia processor **918** may be a sound card, a video capture card, or any other type of media interface, which may also be coupled to one additional devices such as speakers **919**. The legacy device interface **920** is used to couple legacy devices, for example, older styled keyboards and mice, to the processing system **900**.

The processing system **900** illustrated in FIG. 7 is only one exemplary processing system with which the invention may be used. While FIG. 7 illustrates a processing architecture especially suitable for a general purpose computer, such as a personal computer or a workstation, it should be recognized that well known modifications can be made to configure the processing system **900** to become more suitable for use in a variety of applications. For example, many electronic devices which require processing may be implemented using a simpler architecture which relies on a CPU **901** coupled to memory components **908** and/or memory devices **100**. These electronic devices may include, but are not limited to audio/video processors and recorders, gaming consoles, digital television sets, wired or wireless telephones, navigation devices (including system based on the global positioning system (GPS) and/or inertial navigation), and digital cameras and/or recorders. The modifications may include, for example, elimination of unnecessary components, addition of specialized devices or circuits, and/or integration of a plurality of devices.

While the invention has been described and illustrated with reference to specific exemplary embodiments, it should be understood that many modifications and substitutions can be made without departing from the spirit and scope of the invention. Although the embodiment discussed above describes specific numbers of fuses, fuse arrays, lookup tables and number of redundant columns, the present invention is not so limited. Furthermore, although the invention has been described for use in flash memory systems, the invention may be utilized in any memory system which employs column repair using redundant columns. Additionally, although the foregoing discusses application of the invention to column repair using redundant columns, this method and apparatus may also be applied to row repair as well. For row repair, it is not necessary to store in the program array **22** or in each fuse set **200**, the output path selection information loaded into

fuses Fuse₁₀ . . . Fuse₁₂, as described above with reference to FIG. 5. Moreover, although the description provides for a lookup table using complementary bit lines, an alternative embodiment exists where the latches are each individually accessed by a single bit line. Accordingly, the invention is not to be considered as limited by the foregoing description but is only limited by the scope of the claims.

What is claimed as new and desired to be protected by Letters Patent of the United States is:

1. A method of operating a memory device, the method comprising:

monitoring an incoming address to the memory device;
on detecting an address transition in the incoming address,
loading at least one set in a plurality of sets of reloadable latches with stored redundancy information associated with the incoming address, wherein a first subset of the set of reloadable latches is loaded with a defective memory location and a second subset of the set of reloadable latches is loaded with a replacement memory location; and

remapping the defective memory location to the replacement memory location using the at least one loaded set of reloadable latches.

2. The method of claim **1**, wherein the step of remapping includes comparing the incoming address with the defective memory locations stored in the first subsets of the at least one loaded set of reloadable latches.

3. The method of claim **1**, wherein the incoming address is a column address.

4. The method of claim **1**, wherein the incoming address is a row address.

5. The method of claim **1**, wherein the address transition is a change in a sector address of the incoming address.

6. The method of claim **1**, wherein the address transition is a change in a block address of the incoming address.

7. The method of claim **1**, further comprising generating mask data reflecting which of the first subsets of the at least one loaded set of reloadable latches matches the incoming address.

8. A method of operating a memory device, the method comprising:

comparing an incoming address to a plurality of defective memory addresses stored in an array of reloadable latches;

determining if the incoming address is defective; and
if the incoming address is defective, substituting a replacement memory address if the incoming address is determined to be defective.

9. The method of claim **8**, further comprising:

detecting an address transition in the incoming address and reloading the array with a plurality of defective memory addresses and replacement memory address information corresponding to each of the plurality of defective memory addresses.

10. The method of claim **8**, wherein the incoming address is a column address.

11. The method of claim **8**, wherein the incoming address is a row address.

12. The method of claim **8**, wherein the address transition is a change in a sector address of the incoming address.

13. The method of claim **8**, wherein the address transition is a change in a block address of the incoming address.

14. The method of claim **9**, further comprising using a lookup table to store defective memory addresses and corresponding replacement memory address information.

15. The method of claim **14**, further comprising selecting rows of the lookup table corresponding to defective memory

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addresses and replacement memory address information to be loaded into the array of reloadable latches based on at least a portion of the incoming address.

16. A method of operating a memory device, the method comprising:

receiving a first address of a selected a memory line for a memory operation;

receiving a second address;

selecting a third address from a lookup table by decoding the at least portion of the second address to select a row of the lookup table, the second address corresponding to the first address; and

loading the third address into a plurality of reloadable latches,

wherein the memory device is flash memory.

17. The method of claim **16** further comprising using the third address to substitute a redundant memory line for a defective memory line.

18. The method of claim **16**, wherein the lookup table comprises flash memory.

19. The method of claim **17**, further comprising storing a redundant memory line address with the third address in the look up table.

20. The method of claim **19**, further comprising selecting a data output associated with the redundant memory line address.

21. The method of claim **20**, further comprising substituting the first memory line of the selected data output with the selected redundant memory line if the first address corresponds to the defective memory line.

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22. A method of operating a memory device, the method comprising:

receiving, from a first address input, a first address to select a memory line for a memory operation;

receiving, from a second address input, a second address to select a third address from a lookup table, the second address corresponding to the first address;

loading the third address into a plurality of reloadable latches;

detecting a transition in the second address received from the second address input;

using a portion of the transitioned second address to select a new third address; and

loading the new third address into the plurality of reloadable latches in response to the detection.

23. The method of claim **22**, wherein at least one of the memory device or lookup table comprises flash memory.

24. A method of operating a flash memory device, the method comprising:

receiving a first address of a selected a memory line for a memory operation;

receiving a second address to select a third address from a lookup table, the second address corresponding to the first address; and

loading the third address into a plurality of reloadable latches to substitute a redundant memory line for a memory line corresponding to the first address.

* * * * *

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 7,911,872 B2
APPLICATION NO. : 12/371052
DATED : March 22, 2011
INVENTOR(S) : Vinod Lakhani et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In column 9, line 6, in Claim 16, after “selected” delete “a”.

In column 10, line 20, in Claim 24, after “selected” delete “a”.

Signed and Sealed this
Tenth Day of May, 2011

A handwritten signature in black ink that reads "David J. Kappos". The signature is written in a cursive style with a large initial 'D' and 'K'.

David J. Kappos
Director of the United States Patent and Trademark Office